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Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Complete if Known	
				Application Number	09/841,465-Conf. #5373
				Filing Date	April 24, 2001
				First Named Inventor	Seth Haberman
				Art Unit	2623
				Examiner Name	C. L. Parry
Sheet	1	of	2	Attorney Docket Number	2000522.00125US2

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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			

Examiner Signature	/Michael Van Handel/	Date Considered	09/04/2007
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